

# 30V, N-Channel NexFET™ Power MOSFETs

Check for Samples: CSD17510Q5A

### **FEATURES**

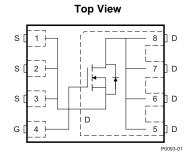
- Ultralow Q<sub>q</sub> and Q<sub>qd</sub>
- **Low Thermal Resistance**
- **Avalanche Rated**
- **Pb Free Terminal Plating**
- **RoHS Compliant**
- **Halogen Free**
- SON 5-mm × 6-mm Plastic Package

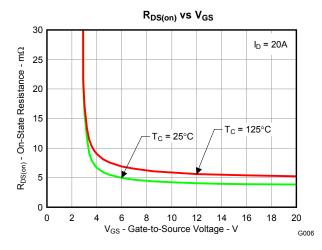
### **APPLICATIONS**

- Point-of-Load Synchronous Buck in Networking, Telecom, and Computing Systems
- **Optimized for Control and Synchronous FET Applications**

#### DESCRIPTION

The NexFET™ power MOSFET has been designed to minimize losses in power conversion applications.





# **PRODUCT SUMMARY**

$V_{DS}$	Drain to Source Voltage 30				
$Q_g$	Gate Charge Total (4.5V)	6.4	nC		
$Q_{gd}$	Gate Charge Gate to Drain	1.9	nC		
R <sub>DS(on)</sub>	Drain to Source On Resistance	$V_{GS} = 4.5V$	5.4	mΩ	
	Drain to Source On Resistance	V <sub>GS</sub> = 10V	4.1	mΩ	
V <sub>GS(th)</sub>	Threshold Voltage	1.5	V		

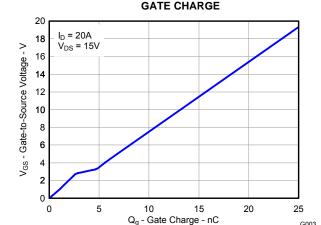
#### ORDERING INFORMATION

Device	Package	Media	Qty	Ship
CSD17510Q5A	SON 5-mm × 6-mm Plastic Package	13-Inch Reel	2500	Tape and Reel

#### **ABSOLUTE MAXIMUM RATINGS**

T <sub>A</sub> = 2	5°C unless otherwise stated	VALUE	UNIT
$V_{DS}$	Drain to Source Voltage	30	V
$V_{GS}$	Gate to Source Voltage	±20	٧
	Continuous Drain Current, T <sub>C</sub> = 25°C	55	Α
I <sub>D</sub>	Continuous Drain Current <sup>(1)</sup>	20	Α
$I_{DM}$	Pulsed Drain Current, T <sub>A</sub> = 25°C <sup>(2)</sup>	129	Α
$P_D$	Power Dissipation <sup>(1)</sup>	3	W
T <sub>J</sub> , T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to 150	°C
E <sub>AS</sub>	Avalanche Energy, single pulse $I_D$ = 54A, L = 0.1mH, $R_G$ = 25 $\Omega$	146	mJ

- (1) Typical  $R_{\theta JA} = 41^{\circ}\text{C/W}$  on 1-inch<sup>2</sup> (6.45-cm<sup>2</sup>), 2-oz. (0.071mm thick) Cu pad on a 0.06-inch (1.52-mm) thick FR4 PCB.
- (2) Pulse duration ≤300µs, duty cycle ≤2%



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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### **ELECTRICAL CHARACTERISTICS**

(T<sub>A</sub> = 25°C unless otherwise stated)

PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
Static Cl	naracteristics				,	
BV <sub>DSS</sub>	Drain to Source Voltage	$V_{GS} = 0V, I_{DS} = 250\mu A$	30			V
I <sub>DSS</sub>	Drain to Source Leakage Current	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 24V			1	μA
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{DS} = 0V, V_{GS} = 20V$			100	nA
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{DS} = V_{GS}, I_{DS} = 250 \mu A$	1	1.5	2.1	V
D	Drain to Course On Registeres	$V_{GS} = 4.5V$ , $I_{DS} = 20A$		5.4	7.3	$m\Omega$
R <sub>DS(on)</sub>	Drain to Source On Resistance	V <sub>GS</sub> = 10V, I <sub>DS</sub> = 20A		4.1	5.2	mΩ
g <sub>fs</sub>	Transconductance	$V_{DS} = 15V, I_{DS} = 20A$		59		S
Dynamic	: Characteristics					
C <sub>iss</sub>	Input Capacitance			960	1250	pF
C <sub>oss</sub>	Output Capacitance	$V_{GS} = 0V, V_{DS} = 15V,$ f = 1MHz		630	820	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	2		51	66	pF
R <sub>G</sub>	Series Gate Resistance			0.85	1.7	Ω
Qg	Gate Charge Total (4.5V)			6.4	8.3	nC
Q <sub>gd</sub>	Gate Charge Gate to Drain	V 45V I 20A		1.9		nC
Q <sub>gs</sub>	Gate Charge Gate to Source	$V_{DS} = 15V, I_{DS} = 20A$		2.7		nC
Q <sub>g(th)</sub>	Gate Charge at Vth			1.5		nC
Q <sub>oss</sub>	Output Charge	$V_{DS} = 13.5V, V_{GS} = 0V$		16		nC
t <sub>d(on)</sub>	Turn On Delay Time			7		ns
t <sub>r</sub>	Rise Time	$V_{DS} = 15V, V_{GS} = 4.5V,$		11		ns
t <sub>d(off)</sub>	Turn Off Delay Time	$I_{DS} = 20A, R_G = 2\Omega$		9		ns
t <sub>f</sub>	Fall Time			4.1		ns
Diode Cl	haracteristics					
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 20A$ , $V_{GS} = 0V$		0.85	1	V
Q <sub>rr</sub>	Reverse Recovery Charge	V 42.5V I 200 di/dt 2000 /v.c		25		nC
t <sub>rr</sub>	Reverse Recovery Time	$V_{DD}$ = 13.5V, $I_F$ = 20A, di/dt = 300A/µs		24		ns

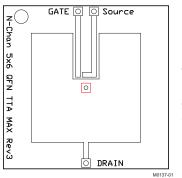
### THERMAL CHARACTERISTICS

(T<sub>A</sub> = 25°C unless otherwise stated)

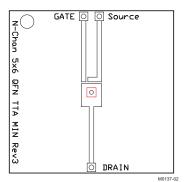
	PARAMETER	MIN	TYP	MAX	UNIT
$R_{\theta JC}$	Thermal Resistance Junction to Case <sup>(1)</sup>			1.6	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient <sup>(1)(2)</sup>			51	°C/W

 <sup>(1)</sup> R<sub>θJC</sub> is determined with the device mounted on a 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu pad on a 1.5-inch x 1.5-inch (3.81-cm x 3.81-cm), 0.06-inch (1.52-mm) thick FR4 PCB. R<sub>θJC</sub> is specified by design, whereas R<sub>θJA</sub> is determined by the user's board design.
 (2) Device mounted on FR4 material with 1-inch² (6.45-cm²), 2-oz. (0.071-mm thick) Cu.





Max  $R_{\theta JA} = 51^{\circ}\text{C/W}$  when mounted on 1 inch² (6.45 cm²) of 2-oz. (0.071-mm thick) Cu.



Max  $R_{\theta JA} = 125^{\circ} C/W$  when mounted on a minimum pad area of 2-oz. (0.071-mm thick) Cu.

### TYPICAL MOSFET CHARACTERISTICS

(T<sub>A</sub> = 25°C unless otherwise stated)

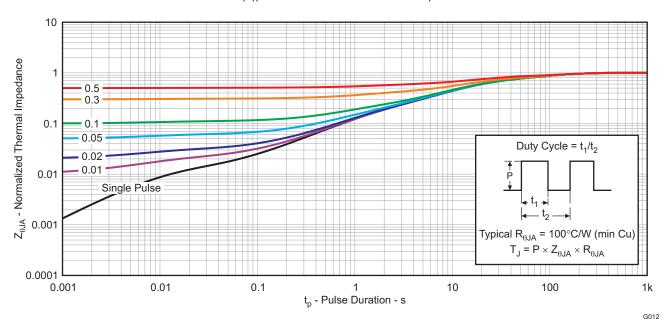


Figure 1. Transient Thermal Impedance



# **TYPICAL MOSFET CHARACTERISTICS (continued)**

(T<sub>A</sub> = 25°C unless otherwise stated)

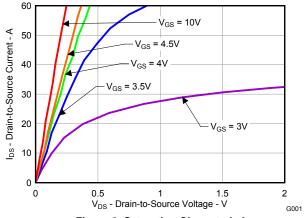


Figure 2. Saturation Characteristics

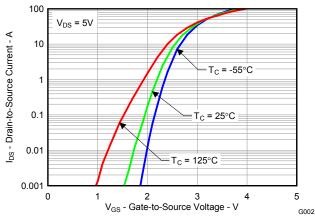


Figure 3. Transfer Characteristics

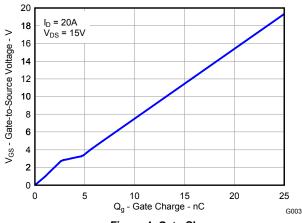


Figure 4. Gate Charge

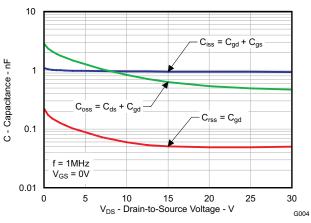


Figure 5. Capacitance

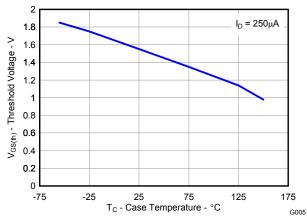


Figure 6. Threshold Voltage vs. Temperature

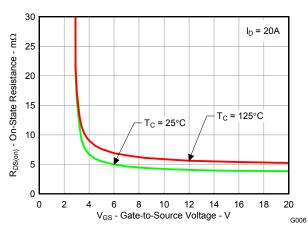


Figure 7. On-State Resistance vs. Gate-to-Source Voltage



## **TYPICAL MOSFET CHARACTERISTICS (continued)**

 $(T_A = 25^{\circ}C \text{ unless otherwise stated})$ 

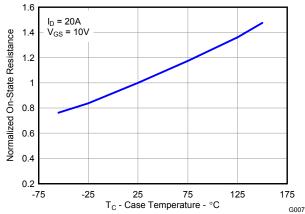


Figure 8. Normalized On-State Resistance vs. Temperature

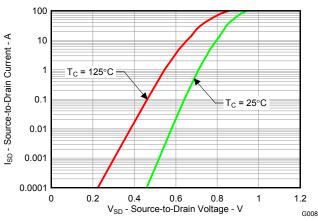


Figure 9. Typical Diode Forward Voltage

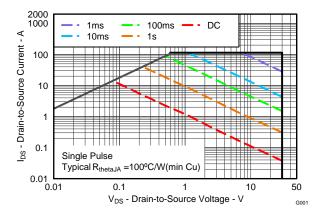


Figure 10. Maximum Safe Operating Area

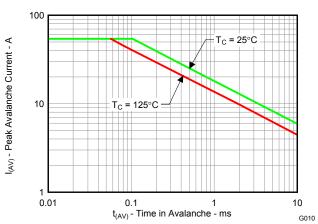


Figure 11. Single Pulse Unclamped Inductive Switching

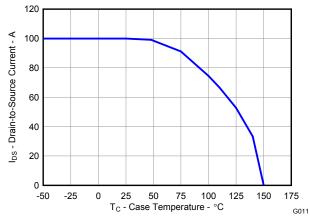
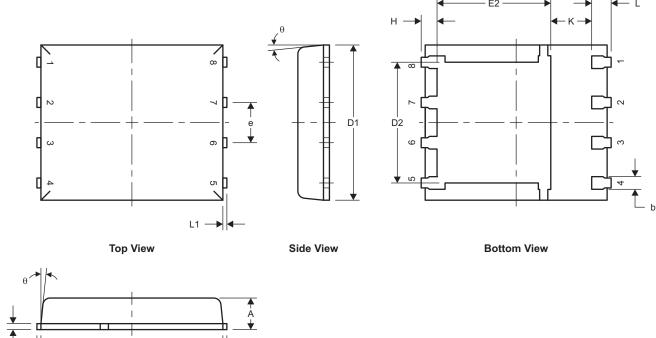


Figure 12. Maximum Drain Current vs. Temperature



# **MECHANICAL DATA**

# **Q5A Package Dimensions**



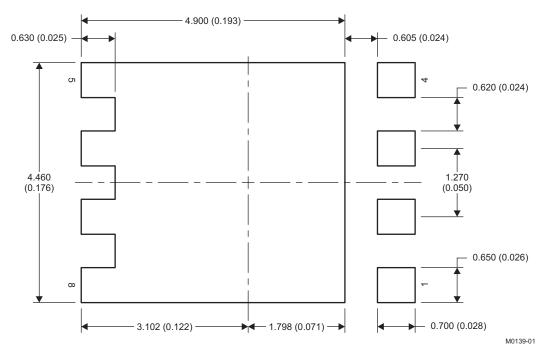
Front View

M0135-01

DIM	MILLIMETERS							
DIN	MIN	NOM	MAX					
А	0.90	1.00	1.10					
b	0.33	0.41	0.51					
С	0.20	0.25	0.34					
D1	4.80	4.90	5.00					
D2	3.61	3.81	4.02					
Е	5.90	6.00	6.10					
E1	5.70	5.75	5.80					
E2	3.38	3.58	3.78					
е	1.17	1.27 0.56	1.37					
Н	0.41		0.71					
K	1.10							
L	0.51	0.61	0.71					
L1	0.06	0.13	0.20					
θ	0°		12°					

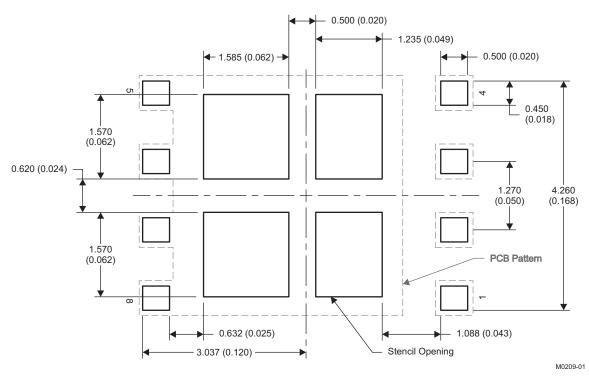


### **Recommended PCB Pattern**



NOTE: Dimensions are in mm (inches).

### **Stencil Recommendation**

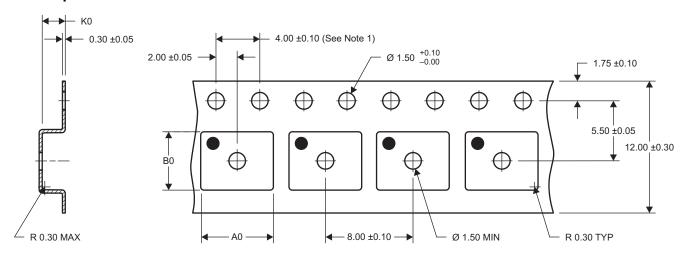


NOTE: Dimensions are in mm (inches).

For recommended circuit layout for PCB designs, see application note SLPA005 – Reducing Ringing Through PCB Layout Techniques.



### **Q5A Tape and Reel Information**



 $A0 = 6.50 \pm 0.10$   $B0 = 5.30 \pm 0.10$  $K0 = 1.40 \pm 0.10$ 

M0138-01

- NOTES: 1. 10-sprocket hole-pitch cumulative tolerance ±0.2
  - 2. Camber not to exceed 1mm in 100mm, noncumulative over 250mm
  - 3. Material: black static-dissipative polystyrene
  - 4. All dimensions are in mm (unless otherwise specified)
  - 5. A0 and B0 measured on a plane 0.3mm above the bottom of the pocket

### **REVISION HISTORY**

Changes from Original (July 2010) to Revision A	Page
Changed the Y axis scale for Figure 5	4
Changes from Revision A (August 2010) to Revision B	Page
• Changed R <sub>DS(on)</sub> Test Conditions From V <sub>GS</sub> = 8V To: V <sub>GS</sub> = 10V	2
Changes from Revision B (September 2010) to Revision C	Page
Absolute Maximum Ratings, changed the E <sub>AS</sub> value from 45 to 146 mJ	1
Changes from Revision C (September 2010) to Revision D	Page
Added the Stencil Recommendation section	7
Changes from Revision D (November 2010) to Revision E	Page
<ul> <li>Changed V<sub>GS</sub> in the Abs Max Ratings table From: +20/-12V To: ±20V</li> <li>Changed from +20/-12V to 20V</li> </ul>	



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Changes from Revision E (July 2011) to Revision F	Page
<ul> <li>Changed the I<sub>D</sub> Continuous Drain Current, T<sub>C</sub> = 25°C value From: 100 A To: 55 A.</li> <li>Changed Figure 10</li> </ul>	
Changes from Revision F (October 2011) to Revision G	Page
Changed Figure 10	5



### PACKAGE OPTION ADDENDUM

6-Feb-2020

#### PACKAGING INFORMATION

Orderable Device	Status	Package Type	_	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
CSD17510Q5A	ACTIVE	VSONP	DQJ	8	2500	Pb-Free (RoHS Exempt)	SN	Level-1-260C-UNLIM	-55 to 150	CSD17510	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

**Green:** TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead/Ball Finish Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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